

Search Notes



Application/Control No.

10/805,023

Examiner

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Applicant(s)/Patent under Reexamination

IKEDA ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	5/06	DN
	7		
	8		
	9		
	10		
714	47		
709	221		
	223		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	5/06	DN
1. US Patent		
2. PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		